

**RoHS** 

COMPLIANT

# N-Channel 500-V (D-S) Super Junction MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V) at T <sub>J</sub> max.	500			
R <sub>DS(on)</sub> max. at 25 °C (Ω)	V <sub>GS</sub> = 10 V	0.243		
Q <sub>g</sub> max. (nC)	66			
Q <sub>gs</sub> (nC)	8			
Q <sub>gd</sub> (nC)	14			
Configuration	Single			

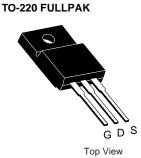
### **FEATURES**

- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Low gate charge (Q<sub>q</sub>)
- Avalanche energy rated (UIS)

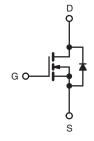
### **APPLICATIONS**

- Computing
  - PC silver box / ATX power supplies









N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	500		
Gate-Source Voltage			$V_{GS}$	± 30	V	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	V at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$	- I <sub>D</sub>	14.5	А	
	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C		9.2		
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	28	1	
Linear Derating Factor				1.25	W/°C	
Single Pulse Avalanche Energy b			E <sub>AS</sub>	136	mJ	
Maximum Power Dissipation			$P_{D}$	156	W	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C		
Drain-Source Voltage Slope	$V_{DS} = 0 V t$	o 80 % V <sub>DS</sub> dV/dt 70		70	V/ns	
Reverse Diode dV/dt <sup>d</sup>			αν/αι	27	V/IIS	
Soldering Recommendations (Peak Temperature) c	for 10 s			300	°C	

### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature.
- b.  $V_{DD}$  = 50 V, starting  $T_J$  = 25 °C, L = 28.2 mH,  $R_q$  = 25  $\Omega$ ,  $I_{AS}$  = 3.1 A.
- c. 1.6 mm from case.
- d.  $I_{SD} \leq I_{D}, \, dI/dt = 100$  A/µs, starting  $T_{J} = 25$  °C.

THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62	°C/W	
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	0.8	C/VV	



# DTN14N50SJ/DTP14N50SJ/DTP14N50FSJ

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PARAMETER	SYMBOL	TES	TEST CONDITIONS		TYP.	MAX.	UNIT
Static		-			•		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		500	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	Reference to 25 °C, I <sub>D</sub> = 1 mA		0.62	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA		-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA
			$V_{GS} = \pm 30 \text{ V}$		-	± 1	μΑ
Zoro Cata Valtaga Drain Current	1	V <sub>DS</sub> =	= 500 V, V <sub>GS</sub> = 0 V		-	10	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 400 \	V <sub>DS</sub> = 400 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C		-	25	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 7.5 A	-	0.243	0.280	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> = 30 V, I <sub>D</sub> = 7.5 A		-	3.9	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V},$ $V_{DS} = 100 \text{ V},$ f = 1  MHz			1162	-	pF
Output Capacitance	C <sub>oss</sub>			-	51	-	
Reverse Transfer Capacitance	$C_{rss}$			-	7	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V		-	55	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	164	-	
Total Gate Charge	Qg			-	33	66	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$V_{GS} = 10 \text{ V}$ $I_D = 7.5 \text{ A}, V_{DS} = 400 \text{ V}$		8	-	nC
Gate-Drain Charge	Q <sub>gd</sub>			-	14	-	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 400 \text{ V}, I_{D} = 12 \text{ A},$ $V_{GS} = 10 \text{ V}, R_{g} = 9.1 \Omega$		-	15	30	- ns
Rise Time	t <sub>r</sub>			-	24	48	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	34	68	
Fall Time	t <sub>f</sub>			-	18	36	
Gate Input Resistance	$R_g$	f = 1 MHz, open drain		-	0.85	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	Is	MOSFET symbol showing the integral reverse p - n junction diode		-	-	14.5	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	28	A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 7.5 A, V <sub>GS</sub> = 0 V		-	-	1.2	V
Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 \text{ °C}, I_F = I_S = 7.5 \text{ A},$ $dI/dt = 100 \text{ A/µs}, V_R = 25 \text{ V}$		-	265	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	3.2	-	μC
Reverse Recovery Current	I <sub>RRM</sub>			-	23	-	Α

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .

### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

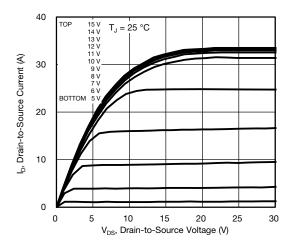


Fig. 1 - Typical Output Characteristics

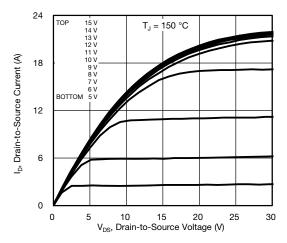


Fig. 2 - Typical Output Characteristics

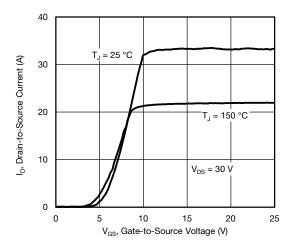


Fig. 3 - Typical Transfer Characteristics

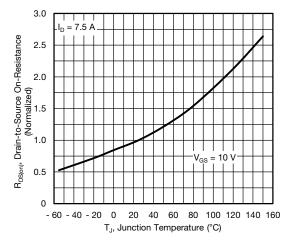


Fig. 4 - Normalized On-Resistance vs. Temperature

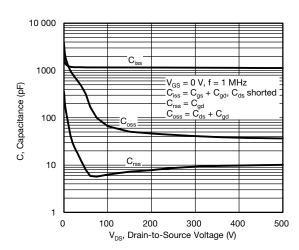


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

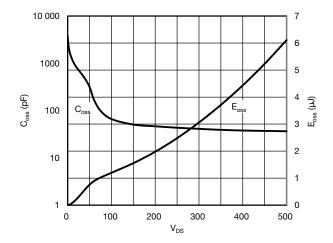


Fig. 6 - Coss and Eoss vs. VDS

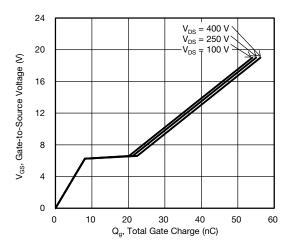


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

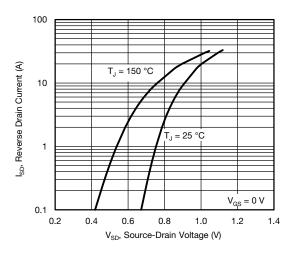


Fig. 8 - Typical Source-Drain Diode Forward Voltage

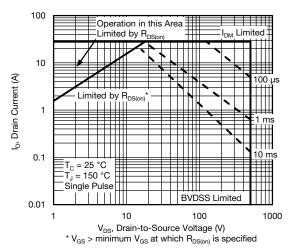


Fig. 9 - Maximum Safe Operating Area

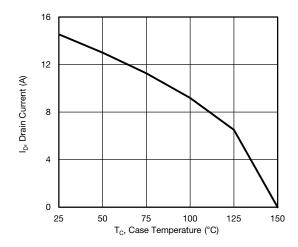


Fig. 10 - Maximum Drain Current vs. Case Temperature

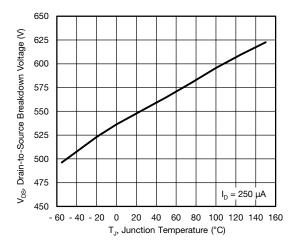


Fig. 11 - Temperature vs. Drain-to-Source Voltage

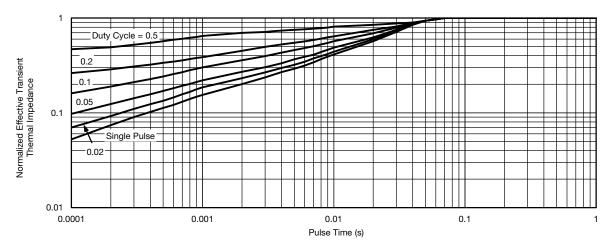


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

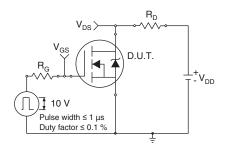


Fig. 13 - Switching Time Test Circuit

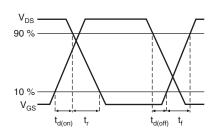


Fig. 14 - Switching Time Waveforms

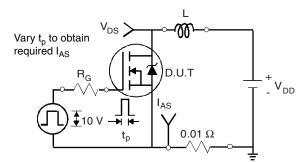


Fig. 15 - Unclamped Inductive Test Circuit

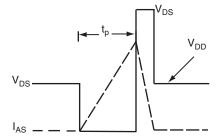


Fig. 16 - Unclamped Inductive Waveforms

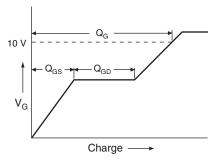


Fig. 17 - Basic Gate Charge Waveform

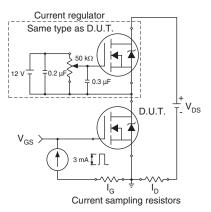
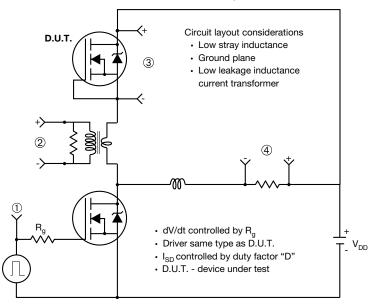


Fig. 18 - Gate Charge Test Circuit

### Peak Diode Recovery dV/dt Test Circuit



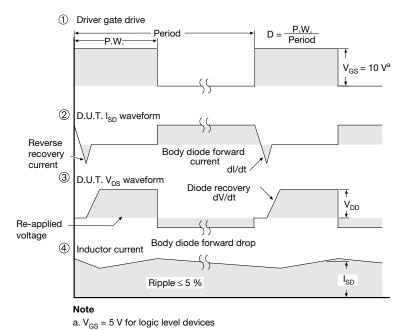


Fig. 19 - For N-Channel





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